

# Search Notes



Application/Control No.

10/541,759

Examiner

Hae M. Hyeon

Applicant(s)/Patent under  
Reexamination

MIYAO ET AL.

Art Unit

2839

## SEARCHED

Class	Subclass	Date	Examiner
Search	Updated	6/07	hnh

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
385	70	6/07	hnh
439	567	↓	↓

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Interference Text Search Done	6/07	hnh